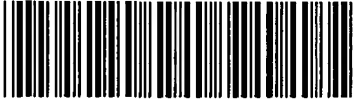


<b>Search Notes</b>  	<b>Application/Control No.</b>  10506766	<b>Applicant(s)/Patent Under Reexamination</b>  BIGEY ET AL.
	<b>Examiner</b>  Shin, Dana	<b>Art Unit</b>  1635

SEARCHED			
Class	Subclass	Date	Examiner
435	6, 15, 193, 375	9-15-06, 5-14-07	DS
514	44	9-15-06, 5-14-07	DS
536	24.5	9-15-06, 5-14-07	DS

SEARCH NOTES		
Search Notes	Date	Examiner
EAST - updated	5-14-07, 1-14-08	DS

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner